16-Bit, Ultra-Low Glitch, Voltage Output Digital-to-Analog Converter with 2.5V, 2ppm/°C Internal Reference

Check for Samples: DAC8560

FEATURES

- **Relative Accuracy: 4LSB**
- **Glitch Energy: 0.15nV-s**
- ***Micro*Power Operation: 510µA at 2.7V**
- **Internal Reference:**
  - **2.5V Reference Voltage (enabled by default)**
  - **0.02% Initial Accuracy**
  - **2ppm/°C Temperature Drift (typ)**
  - **5ppm/°C Temperature Drift (max)**
  - **20mA Sink/Source Capability**
- **Power-On Reset to Zero**
- **Power Supply: +2.7V to +5.5V**
- **16-Bit Monotonic Over Temperature Range**
- **Settling Time: 10µs to ±0.003% FSR**
- **Low-Power Serial Interface with Schmitt-Triggered Inputs**
- **On-Chip Output Buffer Amplifier with Rail-to-Rail Operation**
- **Power-Down Capability**
- **Drop-In Compatible With DAC8531 /01 and DAC8550 /51**
- **Temperature Range: –40°C to +105°C**
- **Available in a Tiny MSOP-8 Package**

APPLICATIONS

- **Process Control**
- **Data Acquisition Systems**
- **Closed-Loop Servo-Control**
- **PC Peripherals**
- **Portable Instrumentation**

DESCRIPTION

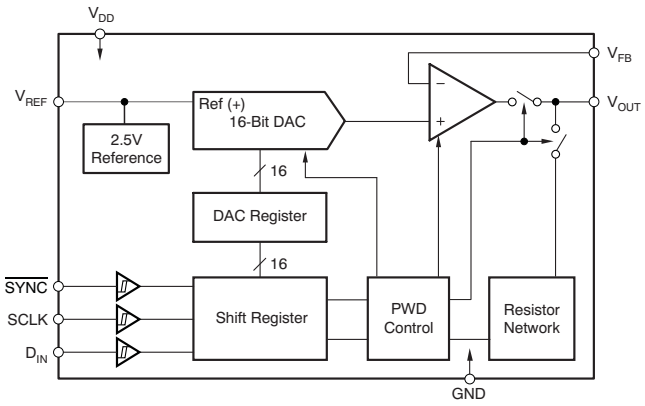
The DAC8560 is a low-power, voltage output, 16-bit digital-to-analog converter (DAC). The DAC8560 includes a 2.5V, 2ppm/°C internal reference (enabled by default), giving a full-scale output voltage range of 2.5V. The internal reference has an initial accuracy of 0.02% and can source up to 20mA at the V_{REF} pin. The device is monotonic, provides very good linearity, and minimizes undesired code-to-code transient voltages (glitch). The DAC8560 uses a versatile 3-wire serial interface that operates at clock rates up to 30MHz. It is compatible with standard SPI™, QSPI™, Microwire™, and digital signal processor (DSP) interfaces.

The DAC8560 incorporates a power-on-reset circuit that ensures the DAC output powers up at zero-scale and remains there until a valid code is written to the device. The DAC8560 contains a power-down feature, accessed over the serial interface, that reduces the current consumption of the device to 1.2µA at 5V.

The low-power consumption, internal reference, and small footprint make this device ideal for portable, battery-operated equipment. The power consumption is 2.6mW at 5V, reducing to 6µW in power-down mode.

The DAC8560 is available in an MSOP-8 package.

FUNCTIONAL BLOCK DIAGRAM



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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

PACKAGING/ORDERING INFORMATION(1)

PRODUCT	MAXIMUM RELATIVE ACCURACY (LSB)	MAXIMUM DIFFERENTIAL NONLINEARITY (LSB)	MAXIMUM REFERENCE DRIFT (ppm/°C)	PACKAGE-LEAD	PACKAGE DESIGNATOR	SPECIFIED TEMPERATURE RANGE	PACKAGE MARKING
DAC8560A	±12	±1	25	MSOP-8	DGK	–40°C TO +105°C	D860
DAC8560B	±8	±1	25				
DAC8560C	±12	±1	5				
DAC8560D	±8	±1	5				

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this data sheet, or see the TI website at www.ti.com.

ABSOLUTE MAXIMUM RATINGS(1)

over operating free-air temperature range (unless otherwise noted)

		UNIT
V_{DD} to GND		–0.3V to 6V
Digital input voltage to GND		–0.3V to $+V_{DD}$ + 0.3V
V_{OUT} to GND		–0.3V to $+V_{DD}$ + 0.3V
Operating temperature range		–40°C to +105°C
Storage temperature range		–65°C to +150°C
Junction temperature range (T_J max)		+150°C
Power dissipation (DGK)		$(T_J \text{ max} – T_A)/\theta_{JA}$
Thermal impedance, θ_{JA}		206°C/W
Thermal impedance, θ_{JC}		44°C/W
ESD rating	Human body model (HBM)	4000V
	Charged device model (CDM)	1500V

(1) Stresses above those listed under *absolute maximum ratings* may cause permanent damage to the device. Exposure to absolute maximum conditions for extended periods may affect device reliability.

ELECTRICAL CHARACTERISTICS

V_{DD} = 2.7V to 5.5V, –40°C to +105°C range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
STATIC PERFORMANCE(1)						
Resolution			16			Bits
Relative accuracy	Measured by line passing through codes 485 and 64714	DAC8560A, DAC8560C		±4	±12	LSB
		DAC8560B, DAC8560D		±4	±8	LSB
Differential nonlinearity	16-bit Monotonic			±0.5	±1	LSB
Zero-code error	Measured by line passing through codes 485 and 64714.			±5	±12	mV
Full-scale error				±0.2	±0.5	% of FSR
Gain error				±0.05	±0.2	% of FSR
Zero-code error drift				±4		µV/°C
Gain temperature coefficient	V_{DD} = 5V			±1		ppm of FSR/°C
	V_{DD} = 2.7V			±3		
PSRR Power supply rejection ratio	Output unloaded			1		mV/V
OUTPUT CHARACTERISTICS(2)						
Output voltage range			0		V_{REF}	V
Output voltage settling time	To ±0.003% FSR, 0200h to FD00h, R_L = 2kΩ, 0pF < C_L < 200pF			8	10	µs
	R_L = 2kΩ, C_L = 500pF			12		
Slew rate				1.8		V/µs
Capacitive load stability	R_L = ∞			470		pF
	R_L = 2kΩ			1000		
Code change glitch impulse	1LSB change around major carry			0.15		nV-s
Digital feedthrough	SCLK toggling, $\overline{SYNC}$ high			0.15		nV-s
DC output impedance	At mid-code input			1		Ω
Short-circuit current	V_{DD} = 5V			50		mA
	V_{DD} = 3V			20		
Power-up time	Coming out of power-down mode V_{DD} = 5V			2.5		µs
	Coming out of power-down mode V_{DD} = 3V			5		
AC PERFORMANCE(2)						
SNR	T_A = +25°C, BW = 20kHz, V_{DD} = 5V, f_{OUT} = 1kHz, 1st 19 harmonics removed for SNR calculation			88		dB
THD				–77		dB
SFDR				79		dB
SINAD				77		dB
DAC output noise density	T_A = +25°C, at mid-code input, f_{OUT} = 1kHz			170		nV/√Hz
DAC output noise	T_A = +25°C, at mid-code input, 0.1Hz to 10Hz			50		μV_{PP}

(1) Linearity calculated using a reduced code range of 485 to 64714; output unloaded.
(2) Ensured by design and characterization, not production tested.

ELECTRICAL CHARACTERISTICS (continued)

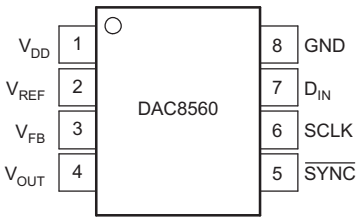
V_{DD} = 2.7V to 5.5V, –40°C to +105°C range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
REFERENCE OUTPUT						
Output voltage		T_A = +25°C	2.4975	2.5	2.5025	V
Initial accuracy		T_A = +25°C	–0.1	±0.004	0.1	%
Output voltage temperature drift		DAC8560A, DAC8560B (3)		5	25	ppm/°C
		DAC8560C, DAC8560D (4)		2	5	
Output voltage noise		f = 0.1Hz to 10Hz		16		μV_{PP}
Output voltage noise density (high-frequency noise)		T_A = +25°C, f = 1MHz, C_L = 0µF		125		nV/√Hz
		T_A = +25°C, f = 1MHz, C_L = 1µF		20		
		T_A = +25°C, f = 1MHz, C_L = 4µF		2		
Load regulation, sourcing (5)		T_A = +25°C		30		µV/mA
Load regulation, sinking (5)		T_A = +25°C		15		µV/mA
Output current load capability (6)				±20		mA
Line regulation		T_A = +25°C		10		µV/V
Long-term stability/drift (aging) (5)		T_A = +25°C, time = 0 to 1900 hours		50		ppm
Thermal hysteresis (5)		First cycle		100		ppm
		Additional cycles		25		
REFERENCE						
Internal reference current consumption		V_{DD} = 5.5V		360		µA
		V_{DD} = 3.6V		348		
External reference current		External V_{REF} = 2.5V, if internal reference is disabled		20		µA
Reference input range			0		V_{DD}	V
Reference input impedance				125		kΩ
LOGIC INPUTS (6)						
Input current				±1		µA
$V_{IN}L$	Logic input LOW voltage	V_{DD} = 5V			0.8	V
		V_{DD} = 3V			0.6	
$V_{IN}H$	Logic input HIGH voltage	V_{DD} = 5V	2.4			V
		V_{DD} = 3V	2.1			
Pin capacitance					3	pF
POWER REQUIREMENTS						
V_{DD}			2.7		5.5	V
I_{DD} (7)	Normal mode	V_{DD} = 3.6V to 5.5V, V_{IH} = V_{DD} and V_{IL} = GND		0.530	0.850	mA
		V_{DD} = 2.7V to 3.6V, V_{IH} = V_{DD} and V_{IL} = GND		0.510	0.840	
	All power-down modes	V_{DD} = 3.6V to 5.5V, V_{IH} = V_{DD} and V_{IL} = GND		1.2	2.5	µA
		V_{DD} = 2.7V to 3.6V, V_{IH} = V_{DD} and V_{IL} = GND		0.7	2.2	
Power dissipation (7)	Normal mode	V_{DD} = 3.6V to 5.5V		2.6	4.7	mW
		V_{DD} = 2.7V to 3.6V		1.5	3.0	
	All power-down modes	V_{DD} = 3.6V to 5.5V		6	14	µW
		V_{DD} = 2.7V to 3.6V		2	8	
TEMPERATURE RANGE						
Specified performance			–40		+105	°C

(3) Reference is trimmed and tested at room temperature, and is characterized from –40°C to +120°C.
(4) Reference is trimmed and tested at two temperatures (+25°C and +105°C), and is characterized from –40°C to +120°C.
(5) Explained in more detail in the Application Information section of this data sheet.
(6) Ensured by design and characterization, not production tested.
(7) Input code = 32768, reference current included, no load.

PIN CONFIGURATION

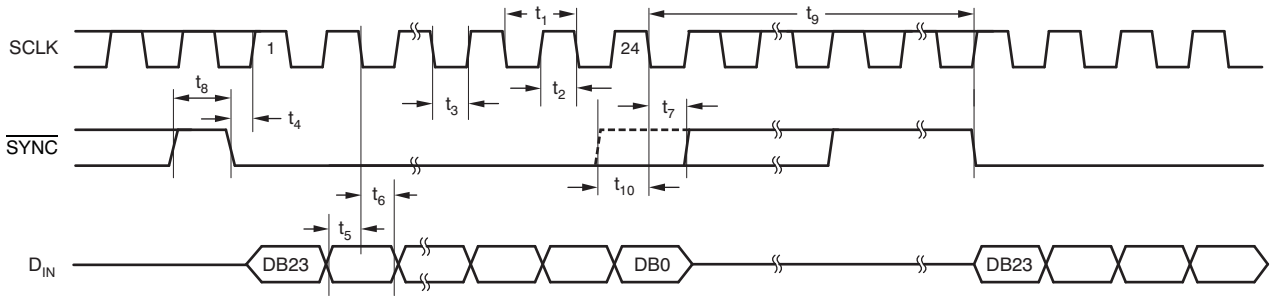
MSOP-8
(Top View)



PIN DESCRIPTIONS

PIN	NAME	DESCRIPTION
1	V_{DD}	Power supply input, 2.7V to 5.5V.
2	V_{REF}	Reference voltage input/output.
3	V_{FB}	Feedback connection for the output amplifier. For voltage output operation, tie to V_{OUT} externally.
4	V_{OUT}	Analog output voltage from DAC. The output amplifier has rail-to-rail operation.
5	$\overline{SYNC}$	Level-triggered control input (active LOW). This is the frame synchronization signal for the input data. When $\overline{SYNC}$ goes LOW, it enables the input shift register, and data is sampled on subsequent falling clock edges. The DAC output updates following the 24th clock. If $\overline{SYNC}$ is taken HIGH before the 24th clock edge, the rising edge of $\overline{SYNC}$ acts as an interrupt, and the write sequence is ignored by the DAC8560. Schmitt-Trigger logic Input.
6	SCLK	Serial clock input. Schmitt-Trigger logic input.
7	D_{IN}	Serial data input. Data is clocked into the 24-bit input shift register on each falling edge of the serial clock input. Schmitt-Trigger logic Input.
8	GND	Ground reference point for all circuitry on the part.

SERIAL WRITE OPERATION



TIMING REQUIREMENTS(1) (2)

V_{DD} = 2.7V to 5.5V, all specifications –40°C to +105°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_1 (3)	SCLK cycle time	V_{DD} = 2.7V to 3.6V	50			ns
		V_{DD} = 3.6V to 5.5V	33			
t_2	SCLK HIGH time	V_{DD} = 2.7V to 3.6V	13			ns
		V_{DD} = 3.6V to 5.5V	13			
t_3	SCLK LOW time	V_{DD} = 2.7V to 3.6V	22.5			ns
		V_{DD} = 3.6V to 5.5V	13			
t_4	$\overline{SYNC}$ to SCLK rising edge setup time	V_{DD} = 2.7V to 3.6V	0			ns
		V_{DD} = 3.6V to 5.5V	0			
t_5	Data setup time	V_{DD} = 2.7V to 3.6V	5			ns
		V_{DD} = 3.6V to 5.5V	5			
t_6	Data hold time	V_{DD} = 2.7V to 3.6V	4.5			ns
		V_{DD} = 3.6V to 5.5V	4.5			
t_7	SCLK falling edge to $\overline{SYNC}$ rising edge	V_{DD} = 2.7V to 3.6V	0			ns
		V_{DD} = 3.6V to 5.5V	0			
t_8	Minimum $\overline{SYNC}$ HIGH time	V_{DD} = 2.7V to 3.6V	50			ns
		V_{DD} = 3.6V to 5.5V	33			
t_9	24th SCLK falling edge to $\overline{SYNC}$ falling edge	V_{DD} = 2.7V to 3.6V	100			ns
		V_{DD} = 3.6V to 5.5V	100			
t_{10}	$\overline{SYNC}$ rising edge to 24th SCLK falling edge (for successful $\overline{SYNC}$ interrupt)	V_{DD} = 2.7V to 3.6V	15			ns
		V_{DD} = 3.6V to 5.5V	15			

(1) All input signals are specified with $t_R = t_F$ = 3ns (10% to 90% of V_{DD}) and timed from a voltage level of (V_{IL} + V_{IH})/2.
(2) See Serial Write Operation timing diagram.
(3) Maximum SCLK frequency is 30MHz at V_{DD} = 3.6V to 5.5V and 20MHz at V_{DD} = 2.7V to 3.6V.

TYPICAL CHARACTERISTICS: Internal Reference

At T_A = +25°C, unless otherwise noted.

INTERNAL REFERENCE VOLTAGE vs TEMPERATURE (Grades C and D)

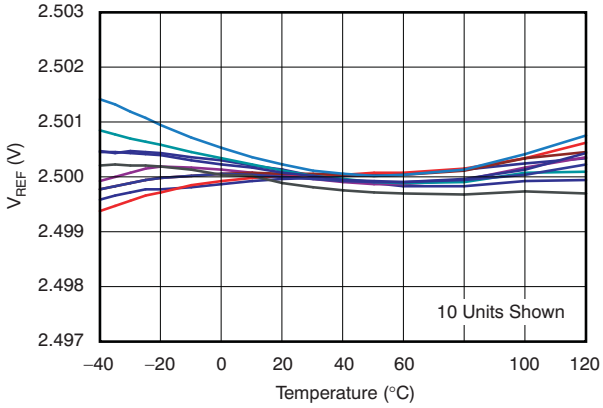


Figure 1.

INTERNAL REFERENCE VOLTAGE vs TEMPERATURE (Grades A and B)

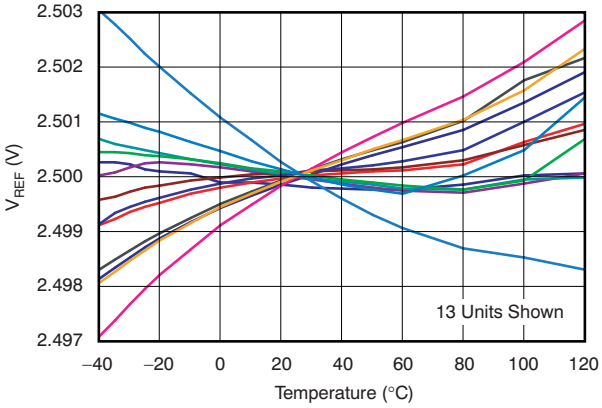


Figure 2.

REFERENCE OUTPUT TEMPERATURE DRIFT (–40°C to +120°C, Grades C and D)

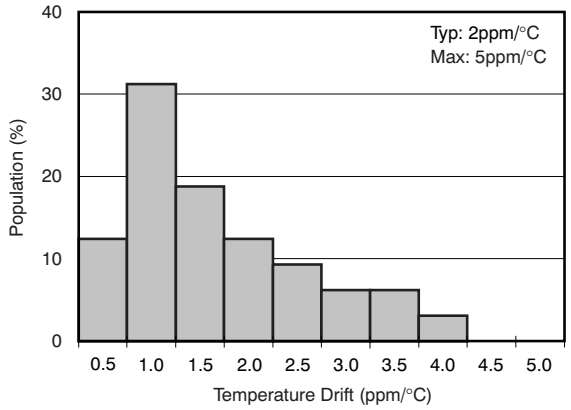


Figure 3.

REFERENCE OUTPUT TEMPERATURE DRIFT (–40°C to +120°, Grades A and B)

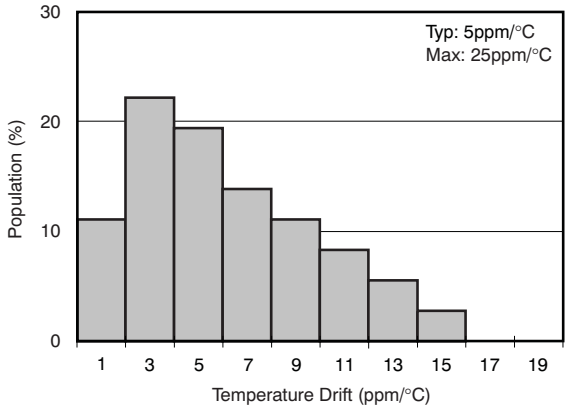


Figure 4.

REFERENCE OUTPUT TEMPERATURE DRIFT (0°C to +120°C, Grades C and D)

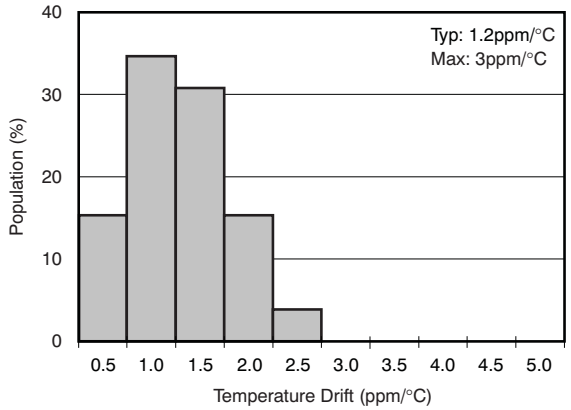


Figure 5.

LONG-TERM STABILITY/DRIFT(1)

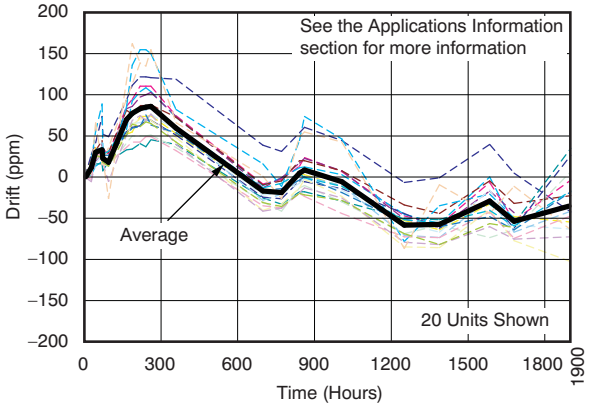


Figure 6.

(1) Explained in more detail in the Application Information section of this data sheet.

TYPICAL CHARACTERISTICS: Internal Reference (continued)

At T_A = +25°C, unless otherwise noted.

INTERNAL REFERENCE NOISE DENSITY vs FREQUENCY (2)

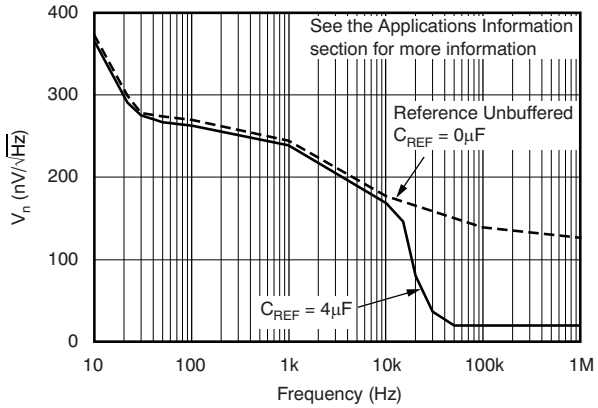


Figure 7.

INTERNAL REFERENCE NOISE 0.1Hz TO 10Hz (2)

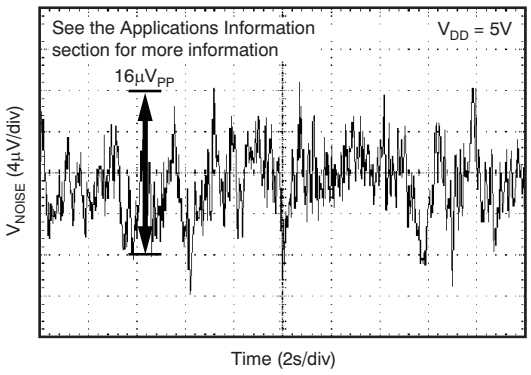


Figure 8.

INTERNAL REFERENCE VOLTAGE vs LOAD CURRENT (Grades C and D)

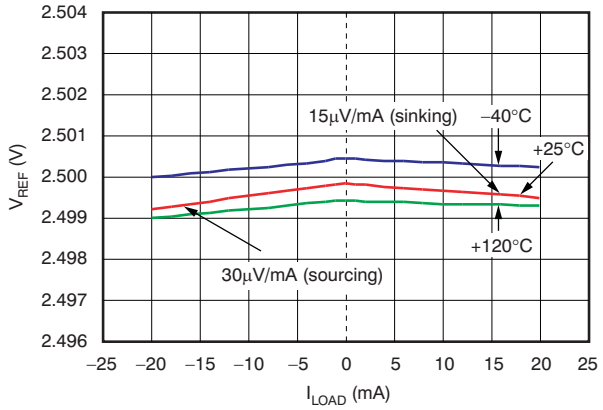


Figure 9.

INTERNAL REFERENCE VOLTAGE vs LOAD CURRENT (Grades A and B)

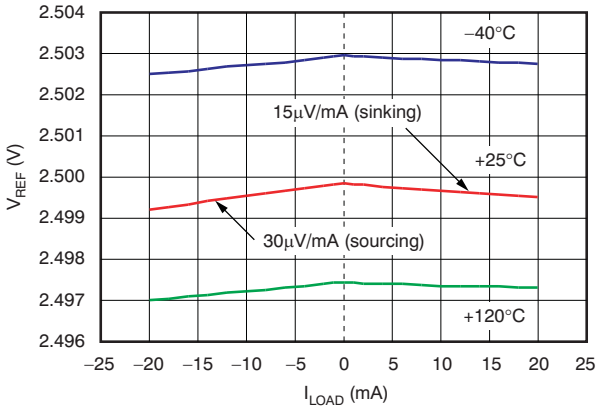


Figure 10.

INTERNAL REFERENCE VOLTAGE vs SUPPLY VOLTAGE (Grades C and D)

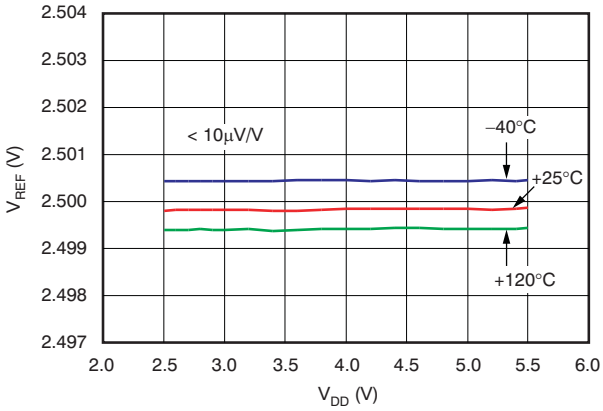


Figure 11.

INTERNAL REFERENCE VOLTAGE vs SUPPLY VOLTAGE (Grades A and B)

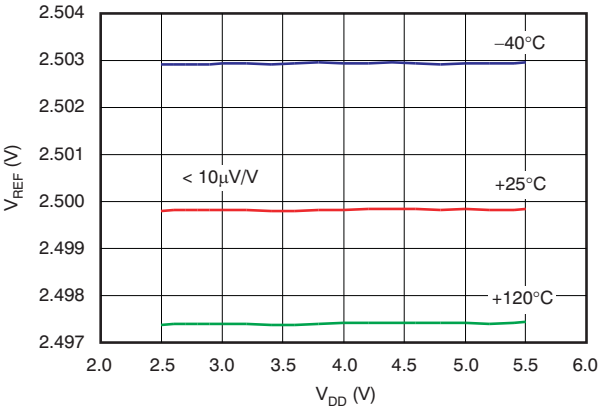


Figure 12.

(2) Explained in more detail in the Application Information section of this data sheet.

TYPICAL CHARACTERISTICS: DAC at V_{DD} = 5V

At T_A = +25°C, external reference used, and DAC output not loaded, unless otherwise noted.

LINEARITY ERROR AND DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE (–40°C)

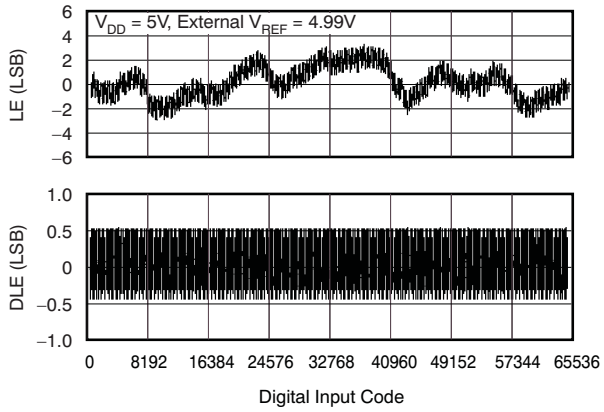


Figure 13.

LINEARITY ERROR AND DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE (+25°C)

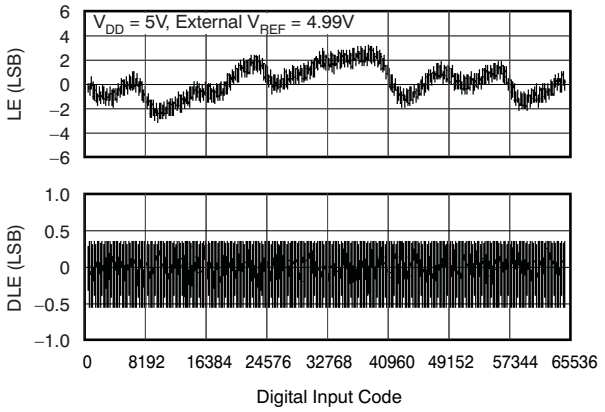


Figure 14.

LINEARITY ERROR AND DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE (+105°C)

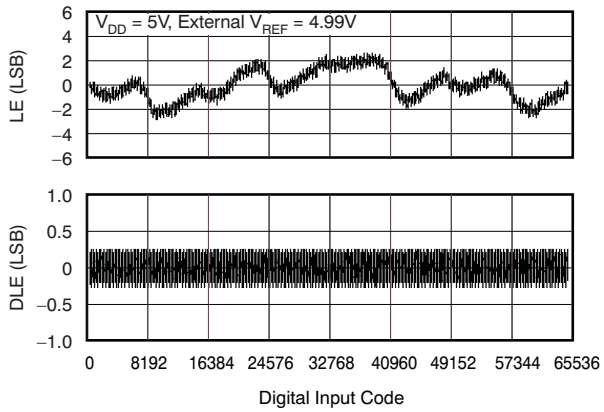


Figure 15.

ZERO-SCALE ERROR vs TEMPERATURE

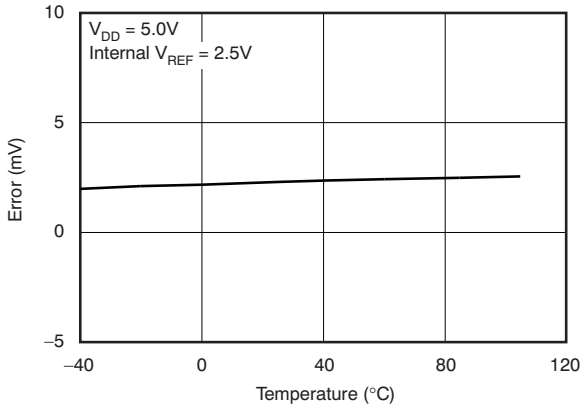


Figure 16.

FULL-SCALE ERROR vs TEMPERATURE

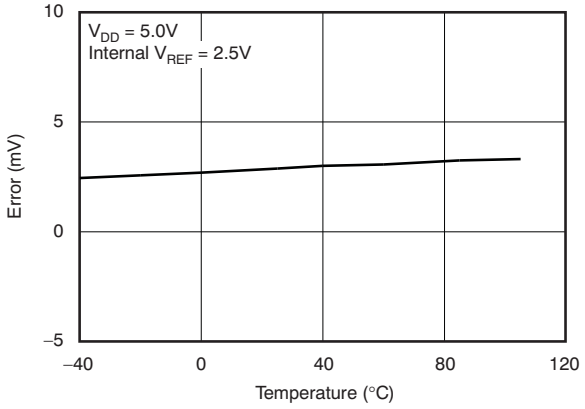


Figure 17.

SOURCE AND SINK CURRENT CAPABILITY

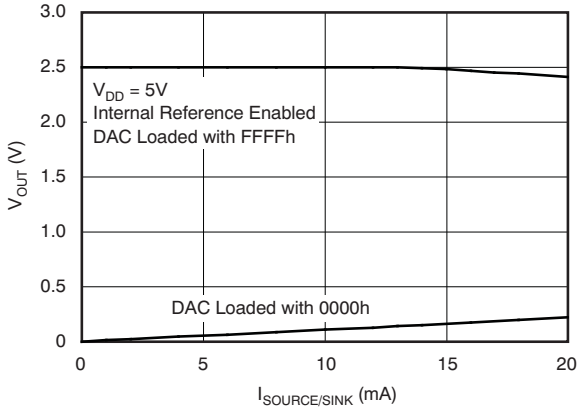


Figure 18.

TYPICAL CHARACTERISTICS: DAC at V_{DD} = 5V (continued)

At T_A = +25°C, external reference used, and DAC output not loaded, unless otherwise noted.

SOURCE AND SINK CURRENT CAPABILITY

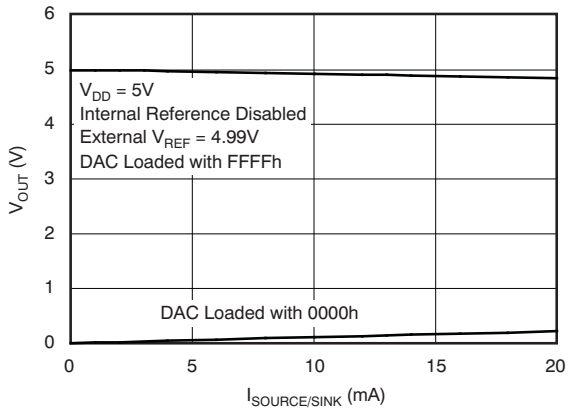


Figure 19.

POWER-SUPPLY CURRENT vs DIGITAL INPUT CODE

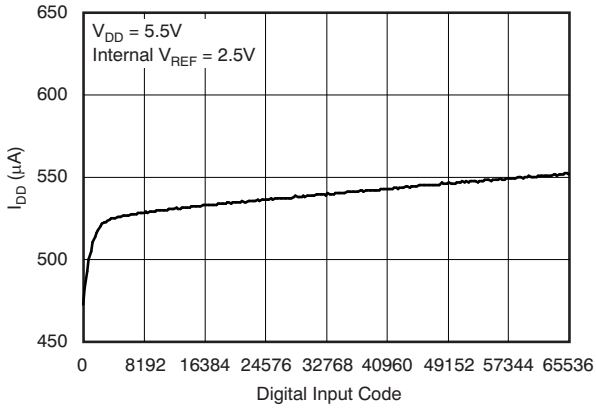


Figure 20.

POWER-SUPPLY CURRENT vs TEMPERATURE

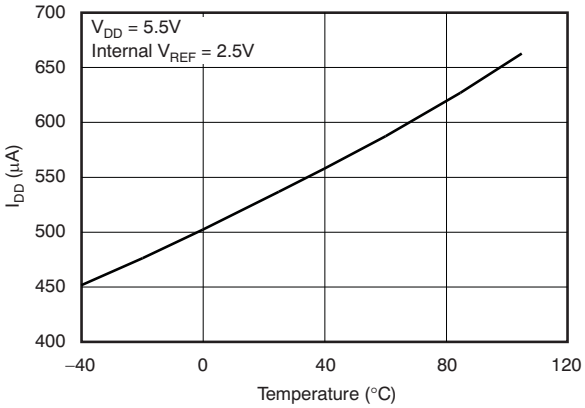


Figure 21.

POWER-SUPPLY CURRENT vs POWER-SUPPLY VOLTAGE

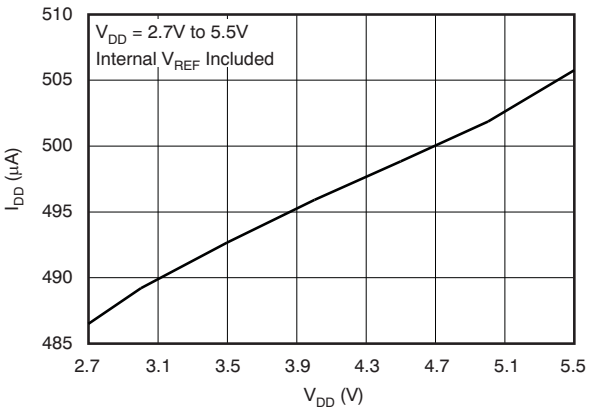


Figure 22.

POWER-DOWN CURRENT vs POWER-SUPPLY VOLTAGE

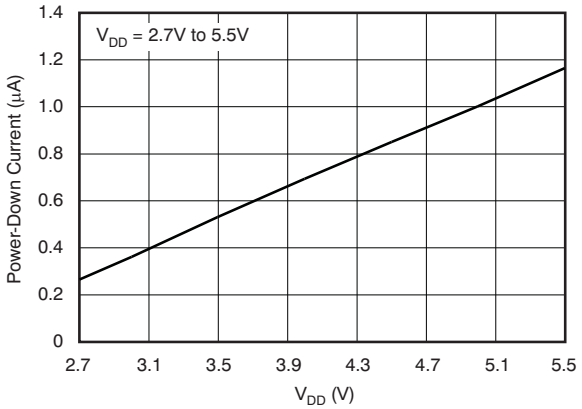


Figure 23.

POWER-SUPPLY CURRENT vs LOGIC INPUT VOLTAGE

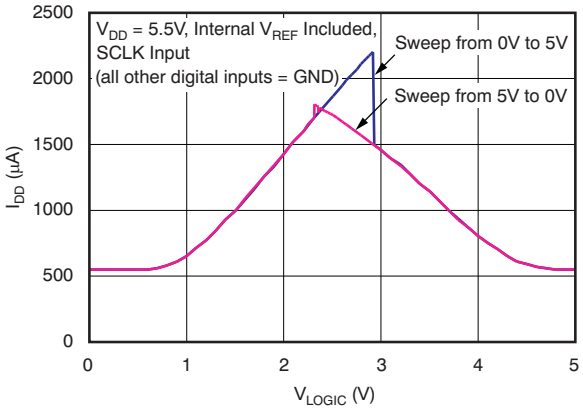


Figure 24.

TYPICAL CHARACTERISTICS: DAC at V_{DD} = 5V (continued)

At T_A = +25°C, external reference used, and DAC output not loaded, unless otherwise noted.

POWER-SUPPLY CURRENT HISTOGRAM

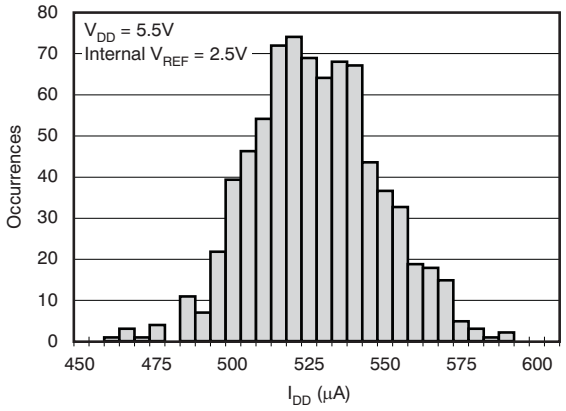


Figure 25.

TOTAL HARMONIC DISTORTION vs OUTPUT FREQUENCY

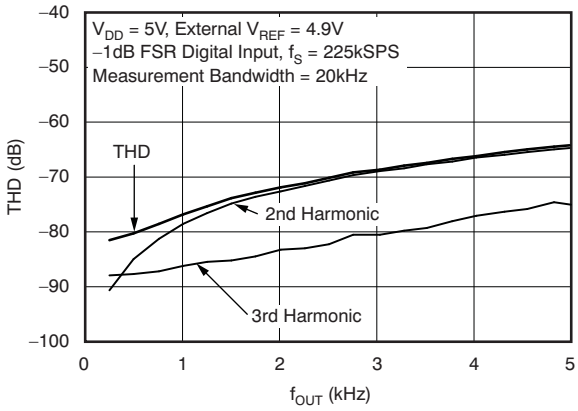


Figure 26.

FULL-SCALE SETTLING TIME: 5V RISING EDGE

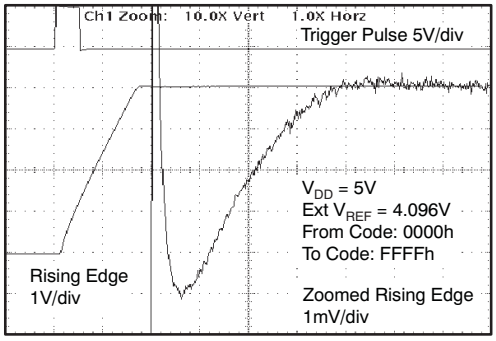


Figure 27.

FULL-SCALE SETTLING TIME: 5V FALLING EDGE

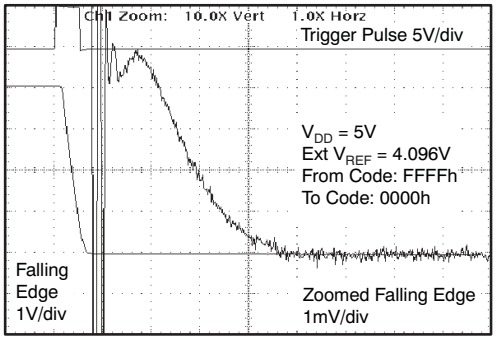


Figure 28.

HALF-SCALE SETTLING TIME: 5V RISING EDGE

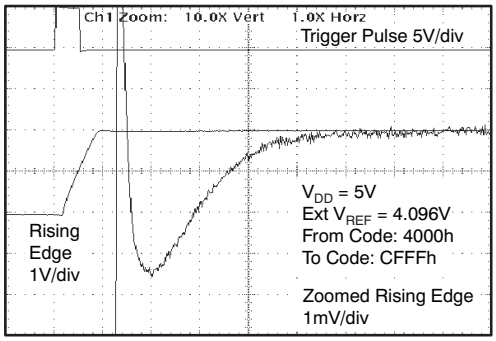


Figure 29.

HALF-SCALE SETTLING TIME: 5V FALLING EDGE

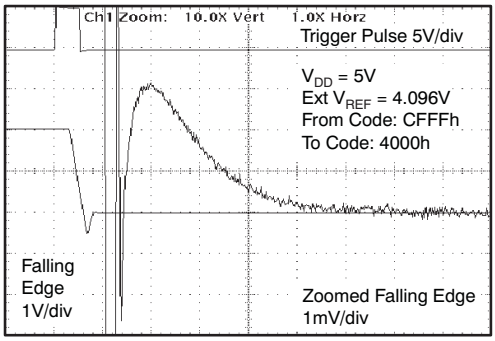


Figure 30.

TYPICAL CHARACTERISTICS: DAC at V_{DD} = 5V (continued)

At T_A = +25°C, external reference used, and DAC output not loaded, unless otherwise noted.

GLITCH ENERGY: 5V, 1LSB STEP, RISING EDGE

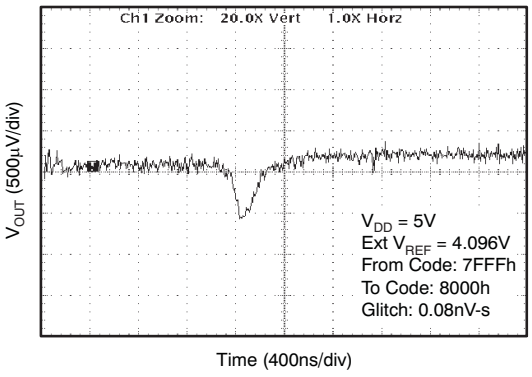


Figure 31.

GLITCH ENERGY: 5V, 1LSB STEP, FALLING EDGE

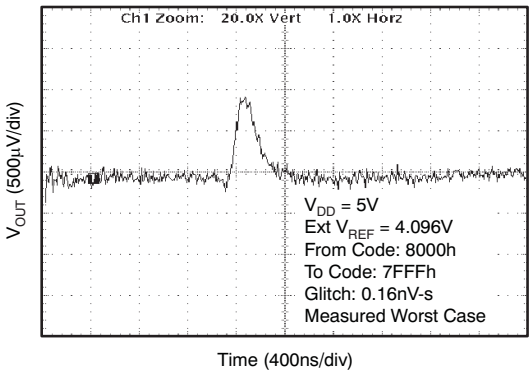


Figure 32.

GLITCH ENERGY: 5V, 16LSB STEP, RISING EDGE

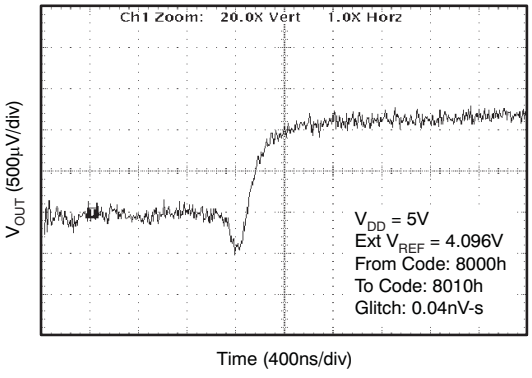


Figure 33.

GLITCH ENERGY: 5V, 16LSB STEP, FALLING EDGE

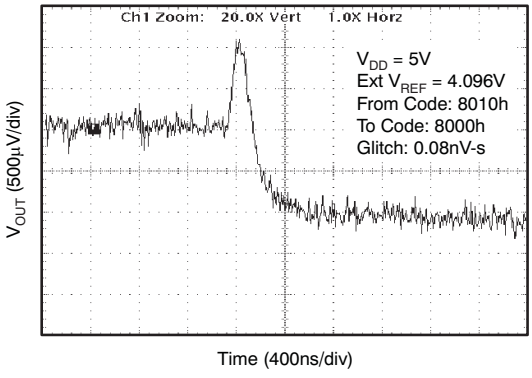


Figure 34.

GLITCH ENERGY: 5V, 256LSB STEP, RISING EDGE

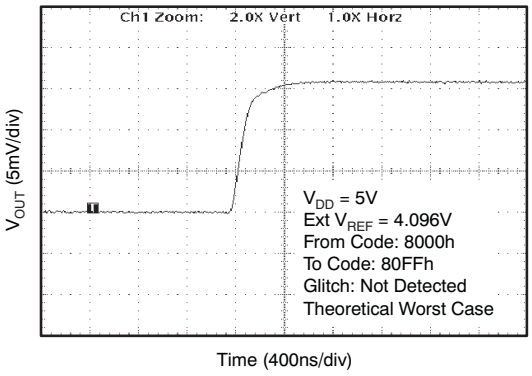


Figure 35.

GLITCH ENERGY: 5V, 256LSB STEP, FALLING EDGE

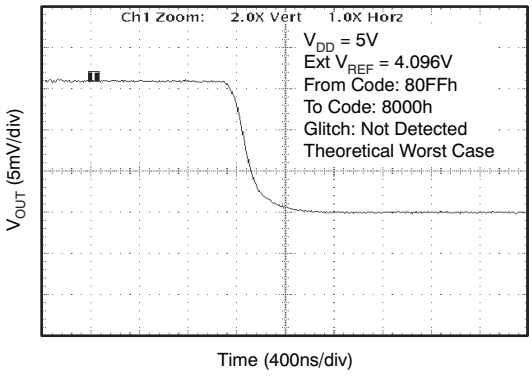


Figure 36.

TYPICAL CHARACTERISTICS: DAC at V_{DD} = 5V (continued)

At T_A = +25°C, external reference used, and DAC output not loaded, unless otherwise noted.

SIGNAL-TO-NOISE RATIO vs OUTPUT FREQUENCY

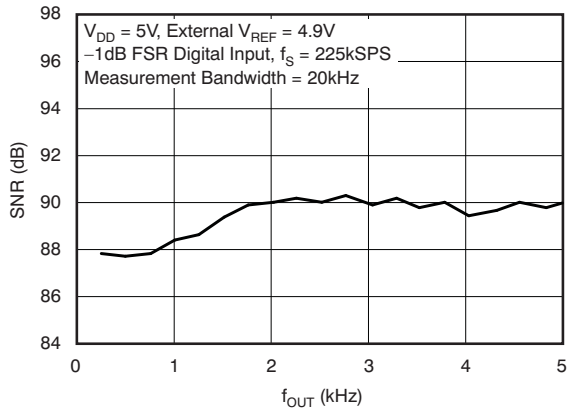


Figure 37.

POWER SPECTRAL DENSITY

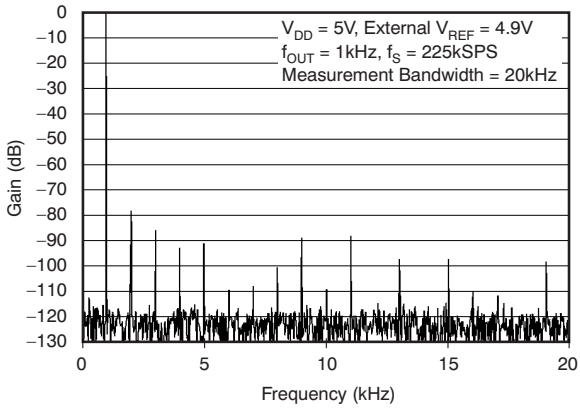


Figure 38.

DAC OUTPUT NOISE DENSITY vs FREQUENCY (1)

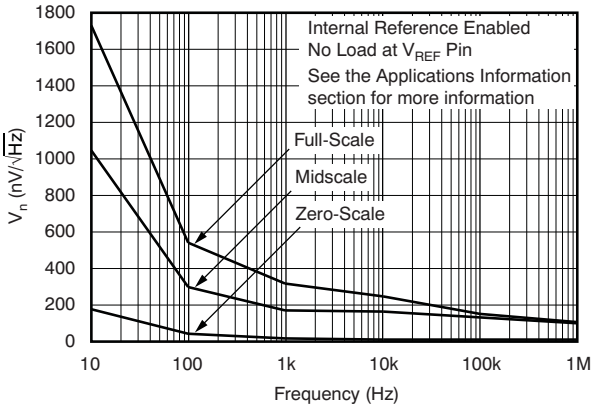


Figure 39.

DAC OUTPUT NOISE DENSITY vs FREQUENCY (1)

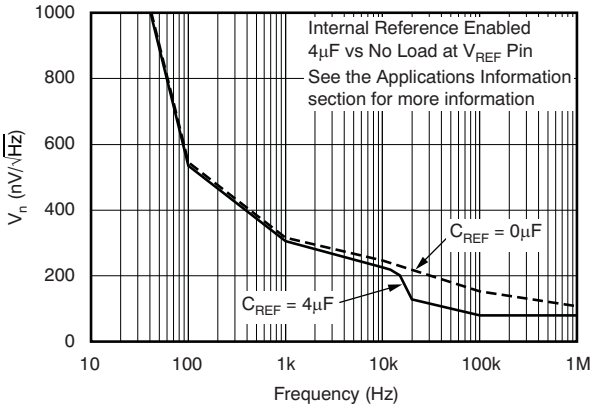


Figure 40.

DAC OUTPUT NOISE 0.1Hz TO 10Hz

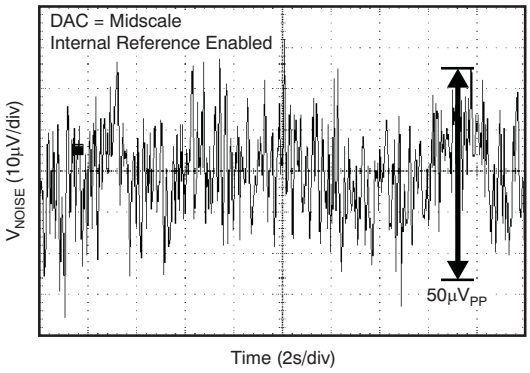


Figure 41.

(1) Explained in more detail in the Application Information section of this data sheet.

TYPICAL CHARACTERISTICS: DAC at V_{DD} = 3.6V

At T_A = +25°C, internal reference used, and DAC output not loaded, unless otherwise noted

POWER-SUPPLY CURRENT vs TEMPERATURE

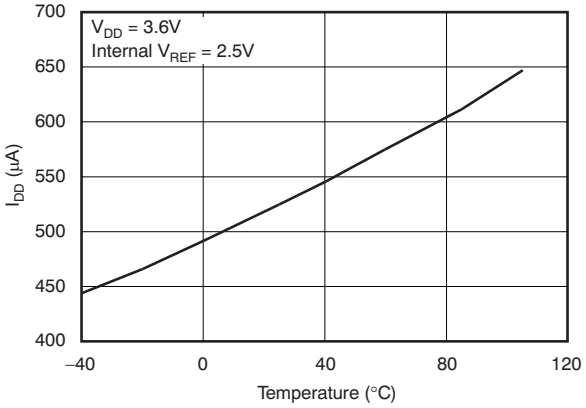


Figure 42.

POWER-SUPPLY CURRENT HISTOGRAM

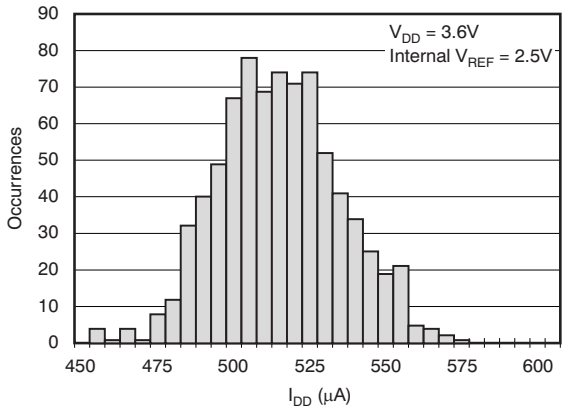


Figure 43.

TYPICAL CHARACTERISTICS: DAC at V_{DD} = 2.7V

At T_A = +25°C, internal reference used, and DAC output not loaded, unless otherwise noted

LINEARITY ERROR AND DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE (–40°C)

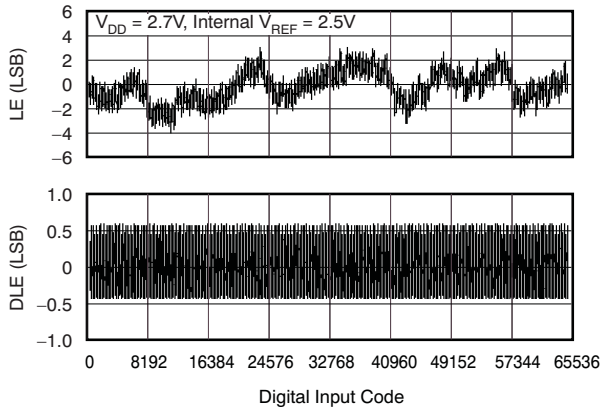


Figure 44.

LINEARITY ERROR AND DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE (+25°C)

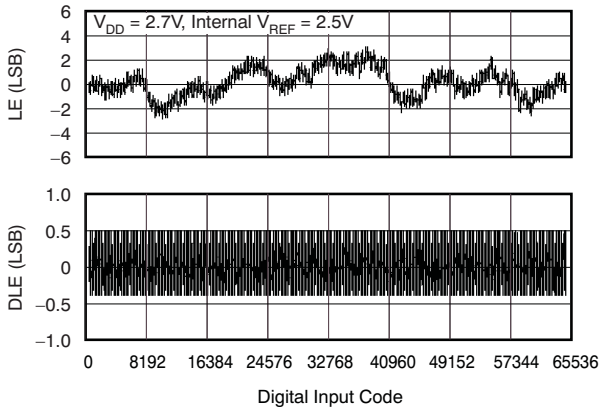


Figure 45.

LINEARITY ERROR AND DIFFERENTIAL LINEARITY ERROR vs DIGITAL INPUT CODE (+105°C)

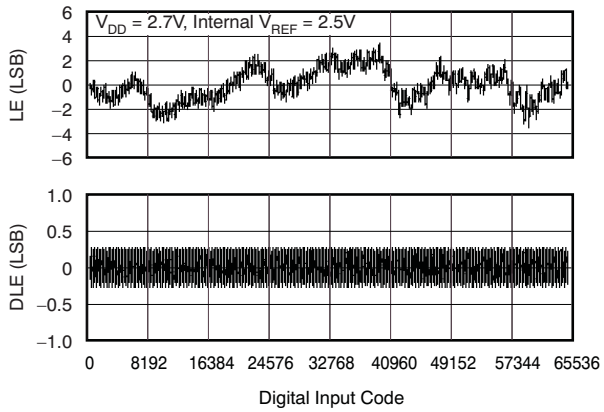


Figure 46.

ZERO-SCALE ERROR vs TEMPERATURE

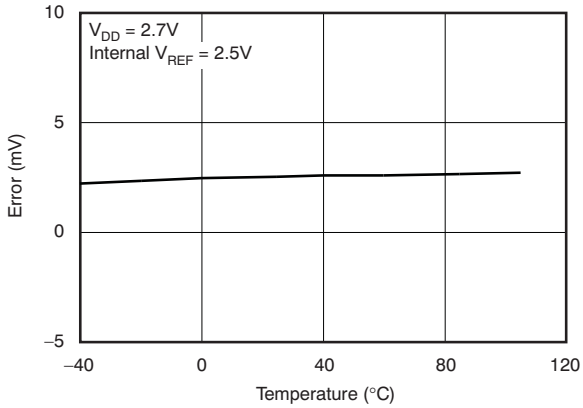


Figure 47.

FULL-SCALE ERROR vs TEMPERATURE

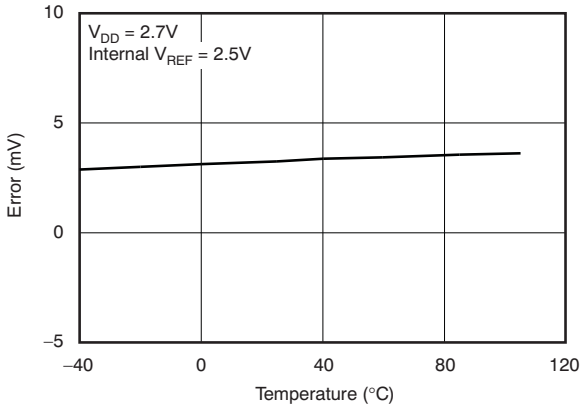


Figure 48.

SOURCE AND SINK CURRENT CAPABILITY

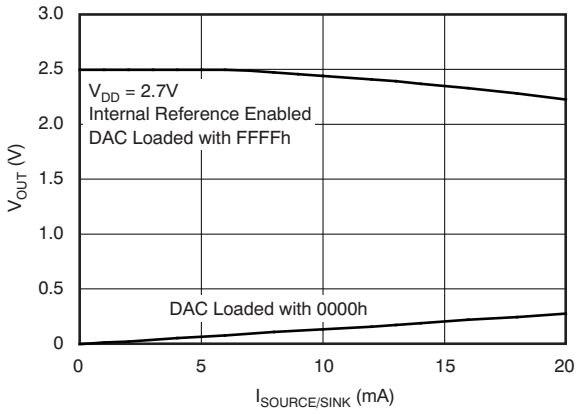


Figure 49.

TYPICAL CHARACTERISTICS: DAC at V_{DD} = 2.7V (continued)

At T_A = +25°C, internal reference used, and DAC output not loaded, unless otherwise noted

SUPPLY CURRENT vs DIGITAL INPUT CODE

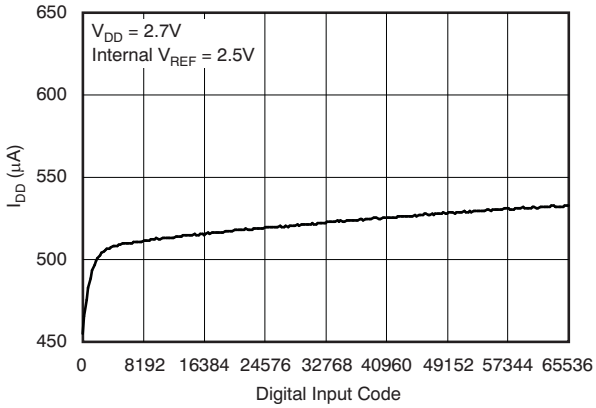


Figure 50.

POWER-SUPPLY CURRENT vs LOGIC INPUT VOLTAGE

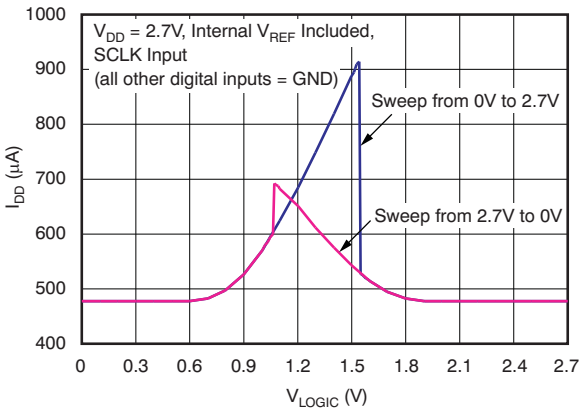


Figure 51.

FULL-SCALE SETTLING TIME: 2.7V RISING EDGE

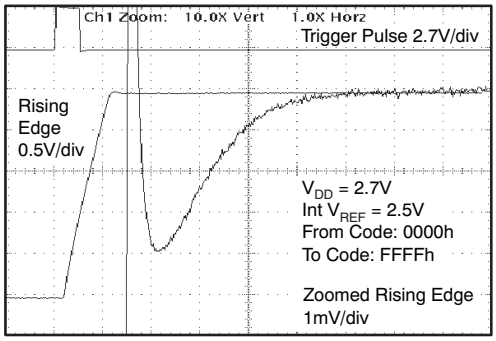


Figure 52.

FULL-SCALE SETTLING TIME: 2.7V FALLING EDGE

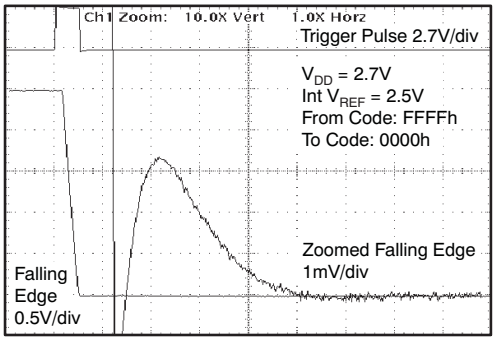


Figure 53.

HALF-SCALE SETTLING TIME: 2.7V RISING EDGE

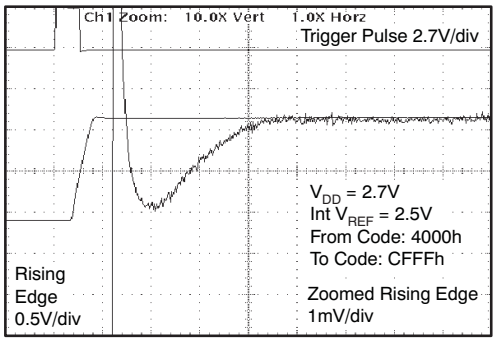


Figure 54.

HALF-SCALE SETTLING TIME: 2.7V FALLING EDGE

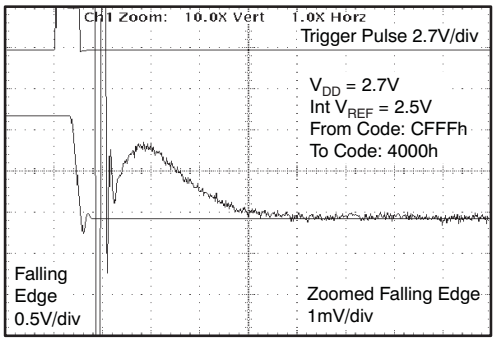


Figure 55.

TYPICAL CHARACTERISTICS: DAC at V_{DD} = 2.7V (continued)

At T_A = +25°C, internal reference used, and DAC output not loaded, unless otherwise noted

GLITCH ENERGY: 2.7V, 1LSB STEP, RISING EDGE

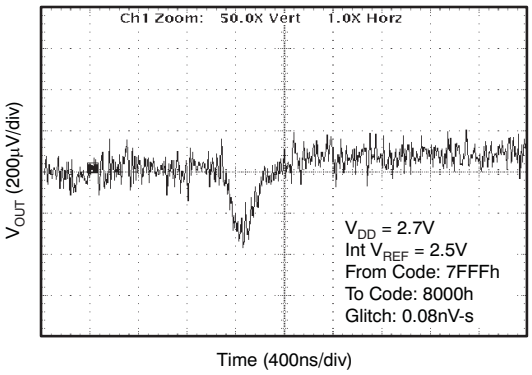


Figure 56.

GLITCH ENERGY: 2.7V, 1LSB STEP, FALLING EDGE

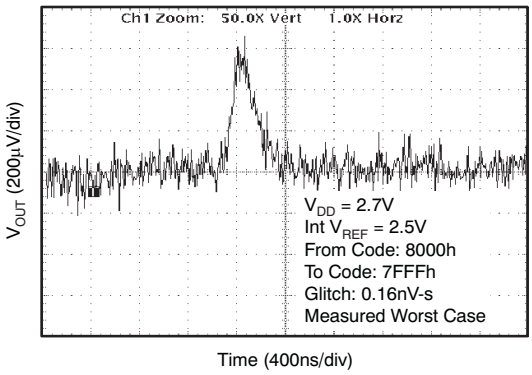


Figure 57.

GLITCH ENERGY: 2.7V, 16LSB STEP, RISING EDGE

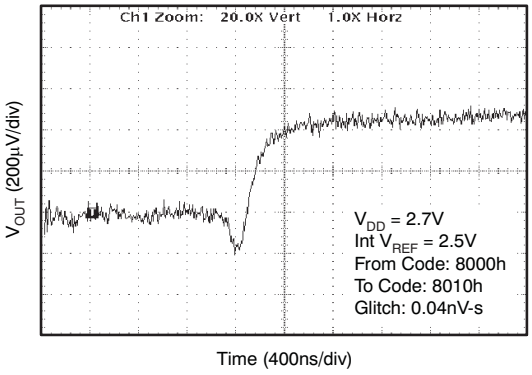


Figure 58.

GLITCH ENERGY: 2.7V, 16LSB STEP, FALLING EDGE

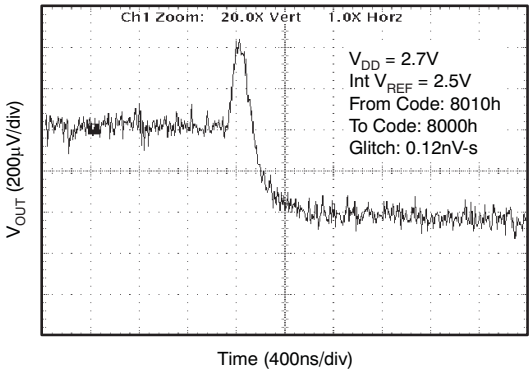


Figure 59.

GLITCH ENERGY: 2.7V, 256LSB STEP, RISING EDGE

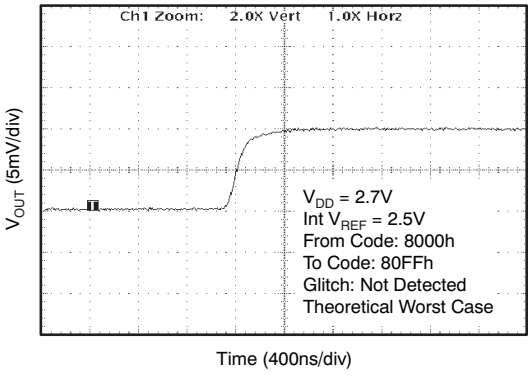


Figure 60.

GLITCH ENERGY: 2.7V, 256LSB STEP, FALLING EDGE

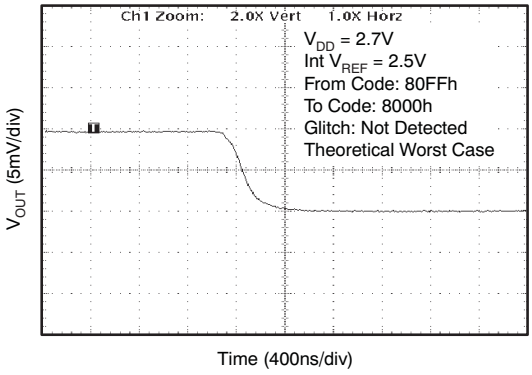


Figure 61.

THEORY OF OPERATION

DIGITAL-TO-ANALOG CONVERTER (DAC)

The DAC8560 architecture consists of a string DAC followed by an output buffer amplifier. Figure 62 shows a block diagram of the DAC architecture.

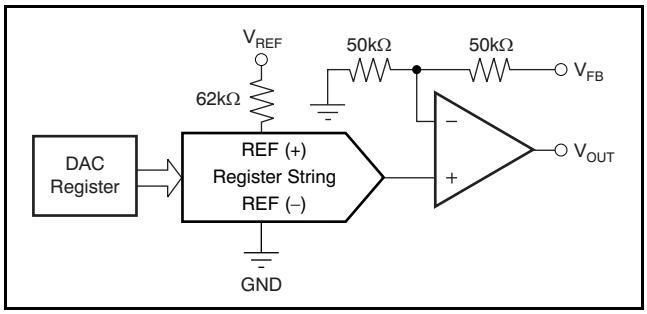


Figure 62. DAC8560 Architecture

The input coding to the DAC8560 is straight binary, so the ideal output voltage is given by:

$$V_{OUT} = \frac{D_{IN}}{65536} \times V_{REF} \quad (1)$$

where D_{IN} = decimal equivalent of the binary code that is loaded to the DAC register; it can range from 0 to 65535.

RESISTOR STRING

The resistor string section is shown in Figure 63. It is simply a string of resistors, each of value R. The code loaded into the DAC register determines at which node on the string the voltage is tapped off to be fed into the output amplifier by closing one of the switches connecting the string to the amplifier. It is monotonic because it is a string of resistors.

OUTPUT AMPLIFIER

The output buffer amplifier is capable of generating rail-to-rail voltages on its output, giving an output range of 0V to V_{DD}. It is capable of driving a load of 2kΩ in parallel with 1000pF to GND. The source and sink capabilities of the output amplifier can be seen in the Typical Characteristics. The slew rate is 1.8V/μs with a full-scale settling time of 8μs with the output unloaded.

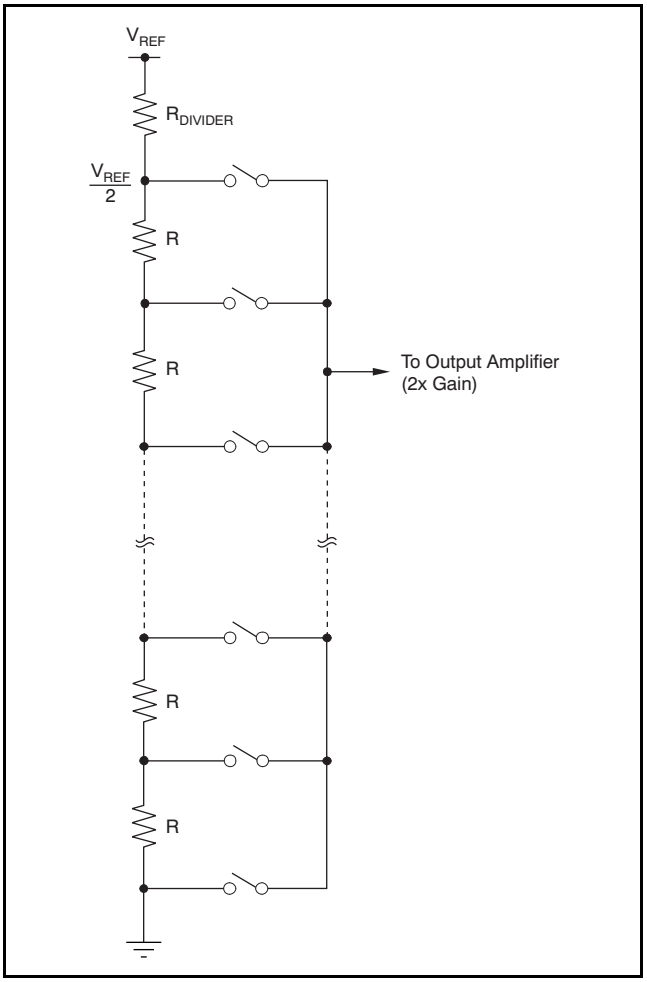


Figure 63. Resistor String

The inverting input of the output amplifier is available at the V_{FB} pin. This feature allows better accuracy in critical applications by tying the V_{FB} point and the amplifier output together directly at the load. Other signal conditioning circuitry may also be connected between these points for specific applications.

INTERNAL REFERENCE

The DAC8560 includes a 2.5V internal reference that is enabled by default. The internal reference is externally available at the V_{REF} pin. A minimum 100nF capacitor is recommended between the reference output and GND for noise filtering.

The internal reference of the DAC8560 is a bipolar transistor-based, precision bandgap voltage reference. The basic bandgap topology is shown in Figure 64. Transistors Q_1 and Q_2 are biased such that the current density of Q_1 is greater than that of Q_2. The difference of the two base-emitter voltages (V_{BE1} - V_{BE2}) has a positive temperature coefficient and is forced across resistor R_1. This voltage is gained up and added to the base-emitter voltage of Q_2, which has a negative temperature coefficient. The resulting output voltage is virtually independent of temperature. The short-circuit current is limited by design to approximately 100mA.

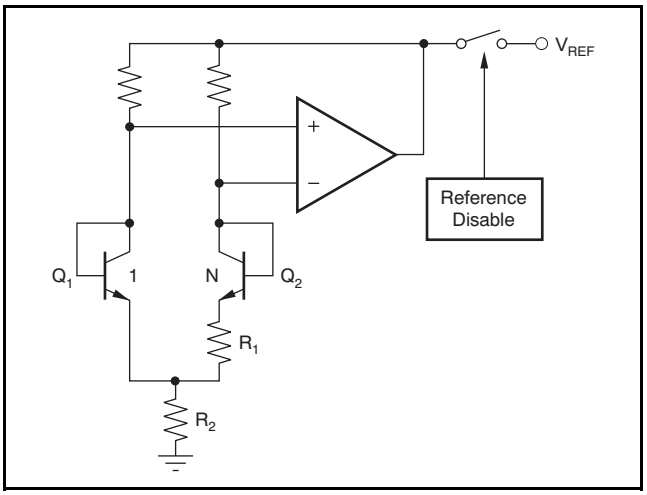


Figure 64. Simplified Schematic of the Bandgap Reference

Enable/Disable Internal Reference

The DAC8560 internal reference is enabled by default; however, the reference can be disabled for debugging or evaluation purposes. A serial command requiring at least two additional SCLK cycles at the end of the 24-bit write sequence (see Serial Interface section) must be used to disable the internal reference. For proper operation, a total of at least 26 SCLK cycles are required for each enable/disable internal reference update sequence, during which $\overline{SYNC}$ must be held low. To disable the internal reference, execute the write sequence illustrated in Table 1 followed by at least two additional SCLK falling edges while $\overline{SYNC}$ is low.

To then enable the reference, either perform a power-cycle to reset the device, or sequentially execute the two write sequences in Table 2 and Table 3. Each of these write sequences must be followed by at least two additional SCLK falling edges while $\overline{SYNC}$ remains low.

During the time that the internal reference is disabled, the DAC will function normally using an external reference. At this point, the internal reference is disconnected from the V_{REF} pin (tri-state). Do not attempt to drive the V_{REF} pin externally and internally at the same time indefinitely.

Table 1. Write Sequence for Disabling the DAC8560 Internal Reference

DB23																							DB0
0	1	0	0	1	0	0	0	0	0	0	0	0	1	0	0	0	0	0	0	0	0	0	1

Table 2. Enabling the DAC8560 Internal Reference (Write Sequence 1 of 2)

DB23																							DB0
0	1	0	0	1	1	0	0	0	0	0	0	0	1	0	0	0	0	0	0	0	0	0	0

Table 3. Enabling the DAC8560 Internal Reference (Write Sequence 2 of 2)

DB23																							DB0
0	1	0	0	1	0	0	1	0	0	0	0	0	1	0	0	0	0	0	0	0	0	0	1

SERIAL INTERFACE

The DAC8560 has a 3-wire serial interface ($\overline{\text{SYNC}}$, SCLK, and D_{IN}) that is compatible with SPI, QSPI, and Microwire interface standards, as well as most DSPs. See the Serial Write Operation timing diagram for an example of a typical write sequence.

The write sequence begins by bringing the $\overline{\text{SYNC}}$ line LOW. Data from the D_{IN} line is clocked into the 24-bit shift register on each falling edge of SCLK. The serial clock frequency can be as high as 30MHz, making the DAC8560 compatible with high-speed DSPs. On the 24th falling edge of the serial clock, the last data bit is clocked in and the programmed function is executed.

At this point, the $\overline{\text{SYNC}}$ line may be kept LOW or brought HIGH. In either case, it must be brought HIGH for a minimum of 33ns before the next write sequence so that a falling edge of $\overline{\text{SYNC}}$ can initiate the next write sequence. As previously mentioned, it must be brought HIGH again before the next write sequence.

INPUT SHIFT REGISTER

The input shift register is 24 bits wide, as shown in Table 4. The first six bits must be '000000'. The next two bits (PD1 and PD0) are control bits that set the desired mode of operation (normal mode or any one of three power-down modes) as indicated in Table 5.

A more complete description of the various modes is located in the Power-Down Modes section. The next 16 bits are the data bits, which are transferred to the DAC register on the 24th falling edge of SCLK under normal operation (see Table 5).

$\overline{\text{SYNC}}$ INTERRUPT

In a normal write sequence, the $\overline{\text{SYNC}}$ line is kept LOW for at least 24 falling edges of SCLK and the DAC is updated on the 24th falling edge. However, if $\overline{\text{SYNC}}$ is brought HIGH before the 24th falling edge, it acts as an interrupt to the write sequence. The shift register is reset, and the write sequence is seen as invalid. Neither an update of the DAC register contents, nor a change in the operating mode occurs, as shown in Figure 65.

POWER-ON RESET

The DAC8560 contains a power-on-reset circuit that controls the output voltage during power up. On power up, all registers are filled with zeros and the output voltage is zero-scale; it remains there until a valid write sequence is made to the DAC. This feature is useful in applications where it is important to know the state of the output of the DAC while it is in the process of powering up.

Table 4. DAC8560 Data Input Register Format

DB23																							DB0
0	0	0	0	0	0	PD 1	PD 0	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0

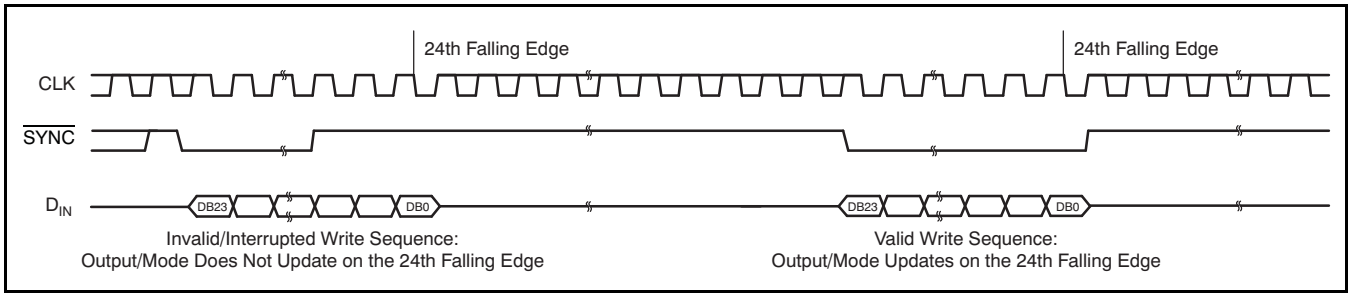


Figure 65. $\overline{\text{SYNC}}$ Interrupt Facility

POWER-DOWN MODES

The DAC8560 supports four separate modes of operation. These modes are programmable by setting two bits (PD1 and PD0) in the control register. Table 5 shows how to control the operating mode with data bits PD1 (DB17) and PD0 (DB16).

Table 5. Operating Modes

PD1 (DB17)	PD0 (DB16)	OPERATING MODE
0	0	Normal operation
0	1	Power-down 1 kΩ to GND
1	0	Power-down 100 kΩ to GND
1	1	Power-down High-Z

When both bits are set to '0', the device works normally with its typical current consumption of 530μA at 5.5V. However, for the three power-down modes, the supply current falls to 1.2μA at 5.5V (0.7μA at 3.6V). Not only does the supply current fall, but the output stage is also internally switched from the output of the amplifier to a resistor network of known values.

The advantage of this switching is that the output impedance of the device is known while it is in power-down mode. As shown in Table 5, there are three different power-down options. V_{OUT} can be connected internally to GND through a 1kΩ resistor, a 100kΩ resistor, or open circuited (High-Z). The output stage is illustrated in Figure 66.

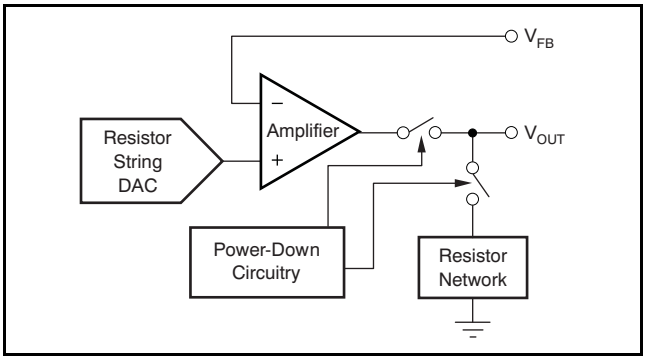


Figure 66. Output Stage During Power Down

All analog circuitry is shut down when the power-down mode is activated. However, the contents of the DAC register are unaffected when in power down. The time to exit power-down is typically 2.5μs for V_{DD} = 5V, and 5μs for V_{DD} = 3V. See the Typical Characteristics for more information.

APPLICATION INFORMATION

INTERNAL REFERENCE

The DAC8560 internal reference does not require an external load capacitor for stability because it is stable with any capacitive load. However, for improved noise performance, an external load capacitor of 150nF or larger connected to the V_{REF} output is recommended. Figure 67 shows the typical connections required for operation of the DAC8560 internal reference. A supply bypass capacitor at the V_{DD} input is also recommended.

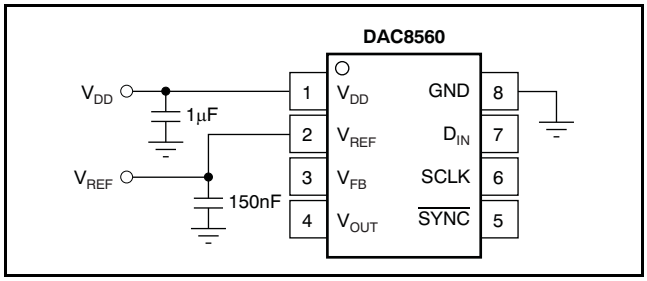


Figure 67. Typical Connections for Operating the DAC8560 Internal Reference

Supply Voltage

The DAC8560 internal reference features an extremely low dropout voltage. It can be operated with a supply of only 5mV above the reference output voltage in an unloaded condition. For loaded conditions, refer to the Load Regulation section. The stability of the DAC8560 internal reference with variations in supply voltage (line regulation, DC PSRR) is also exceptional. Within the specified supply voltage range of 2.7V to 5.5V, the variation at V_{REF} is smaller than 10µV/V; see the Typical Characteristics.

Temperature Drift

The DAC8560 internal reference is designed to exhibit minimal drift error, defined as the change in reference output voltage over varying temperature. The drift is calculated using the *box* method, which is described by Equation 2:

$$\text{Drift Error} = \left(\frac{V_{REF\_MAX} - V_{REF\_MIN}}{V_{REF} \times T_{RANGE}} \right) \times 10^6 \ (\text{ppm}/^\circ\text{C}) \quad (2)$$

Where:

V_{REF_MAX} = maximum reference voltage observed within temperature range T_{RANGE}.

V_{REF_MIN} = minimum reference voltage observed within temperature range T_{RANGE}.

V_{REF} = 2.5V, target value for reference output voltage.

The DAC8560 internal reference (grades C and D) features an exceptional typical drift coefficient of 2ppm/°C from –40°C to +120°C. Characterizing a large number of units, a maximum drift coefficient of 5ppm/°C (grades C and D) is observed. Temperature drift results are summarized in the Typical Characteristics.

Noise Performance

Typical 0.1Hz to 10Hz voltage noise can be seen in Figure 8, *Internal Reference Noise*. Additional filtering can be used to improve output noise levels, although care should be taken to ensure the output impedance does not degrade the AC performance. The output noise spectrum at V_{REF} without any external components is depicted in Figure 7, *Internal Reference Noise Density vs Frequency*. Another noise density spectrum is also shown in Figure 7, which was obtained using a 4µF load capacitor at V_{REF} for noise filtering. Internal reference noise impacts the DAC output noise; see the DAC Noise Performance section for more details.

Load Regulation

Load regulation is defined as the change in reference output voltage as a result of changes in load current. The load regulation of the DAC8560 internal reference is measured using force and sense contacts as pictured in Figure 68. The force and sense lines reduce the impact of contact and trace resistance, resulting in accurate measurement of the load regulation contributed solely by the DAC8560 internal reference. Measurement results are summarized in the Typical Characteristics. Force and sense lines should be used for applications requiring improved load regulation.

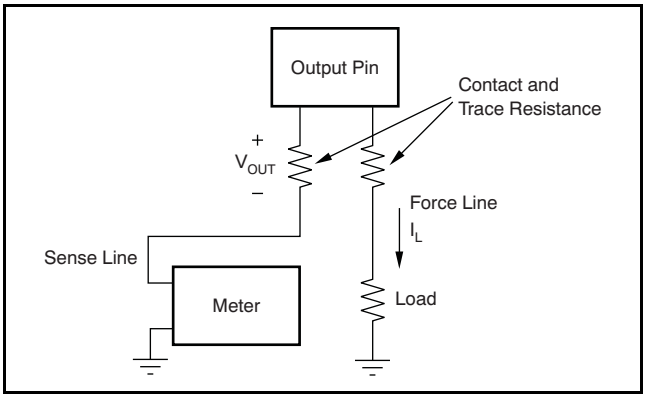


Figure 68. Accurate Load Regulation of the DAC8560 Internal Reference

Long-Term Stability

Long-term stability/aging refers to the change of the output voltage of a reference over a period of months or years. This effect lessens as time progresses, as shown in Figure 6, the typical long-term stability curve. The typical drift value for the DAC8560 internal reference is 50ppm from 0 hours to 1900 hours. This parameter is characterized by powering-up and measuring 20 units at regular intervals for a period of 1900 hours.

Thermal Hysteresis

Thermal hysteresis for a reference is defined as the change in output voltage after operating the device at +25°C, cycling the device through the specified temperature range, and returning to +25°C. It is expressed in Equation 3:

$$V_{HYST} = \left(\frac{|V_{REF\_PRE} - V_{REF\_POST}|}{V_{REF\_NOM}} \right) \times 10^6 \text{ (ppm)} \quad (3)$$

Where:

V_{HYST} = thermal hysteresis.

V_{REF_PRE} = output voltage measured at +25°C pre-temperature cycling.

V_{REF_POST} = output voltage measured after the device has been cycled through the temperature range of –40°C to +120°C, and returned to +25°C.

DAC NOISE PERFORMANCE

Typical noise performance for the DAC8560 with the internal reference enabled is shown in Figure 39 to Figure 41. Output noise spectral density at pin V_{OUT} versus frequency is depicted in Figure 39 for full-scale, midscale, and zero scale input codes. The typical noise density for midscale code is 170nV/$\sqrt{Hz}$ at 1kHz and 100nV/$\sqrt{Hz}$ at 1MHz. High-frequency noise can be improved by filtering the reference noise as shown in Figure 40, where a 4µF load capacitor is connected to the V_{REF} pin and compared to the no-load condition. Integrated output noise between 0.1Hz and 10Hz is close to 50µV_{PP} (midscale), as shown in Figure 41.

BIPOLAR OPERATION USING THE DAC8560

The DAC8560 has been designed for single-supply operation, but a bipolar output range is also possible using the circuit in either Figure 69 or Figure 70. The circuit shown gives an output voltage range of ±V_{REF}. Rail-to-rail operation at the amplifier output is achievable using an OPA703 as the output amplifier.

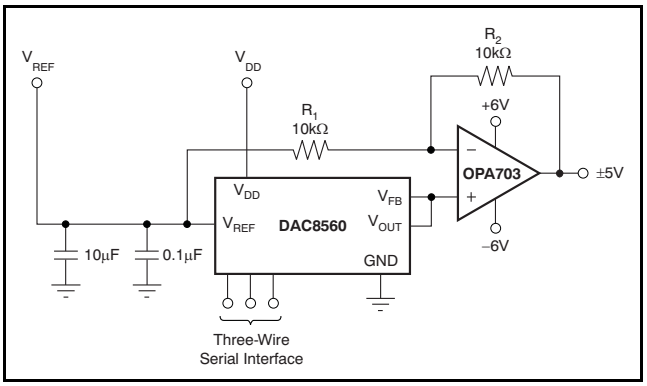


Figure 69. Bipolar Output Range Using External Reference at 5V

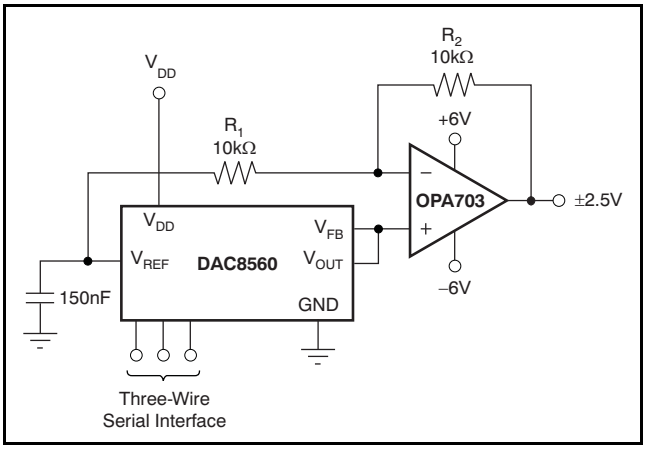


Figure 70. Bipolar Output Range Using Internal Reference

The output voltage for any input code can be calculated as using Equation 4:

$$V_O = \left[V_{REF} \times \left(\frac{D}{65536} \right) \times \left(\frac{R_1 + R_2}{R_1} \right) - V_{REF} \times \left(\frac{R_2}{R_1} \right) \right] \quad (4)$$

where D represents the input code in decimal (0–65535).

With V_{REF} = 5V, R_1 = R_2 = 10kΩ.

$$V_O = \left(\frac{10 \times D}{65536} \right) - 5V \quad (5)$$

This result has an output voltage range of ±5V with 0000h corresponding to a –5V output and FFFFh corresponding to a 5V output, as shown in Figure 69. Similarly, using the internal reference, a ±2.5V output voltage range can be achieved, as shown in Figure 70.

MICROPROCESSOR INTERFACING

DAC8560 TO 8051 Interface

See Figure 71 for a serial interface between the DAC8560 and a typical 8051-type microcontroller. The setup for the interface is as follows: TXD of the 8051 drives SCLK of the DAC8560, while RXD drives the serial data line of the device. The SYNC signal is derived from a bit-programmable pin on the port of the 8051. In this case, port line P3.3 is used. When data is to be transmitted to the DAC8560, P3.3 is taken LOW. The 8051 transmits data in 8-bit bytes; thus, only eight falling clock edges occur in the transmit cycle. To load data to the DAC, P3.3 is left LOW after the first eight bits are transmitted, then a second write cycle is initiated to transmit the second byte of data. P3.3 is taken HIGH following the completion of the third write cycle. The 8051 outputs the serial data in a format which has the LSB first. The DAC8560 requires its data with the MSB as the first bit received. The 8051 transmit routine must therefore take this into account, and *mirror* the data as needed.

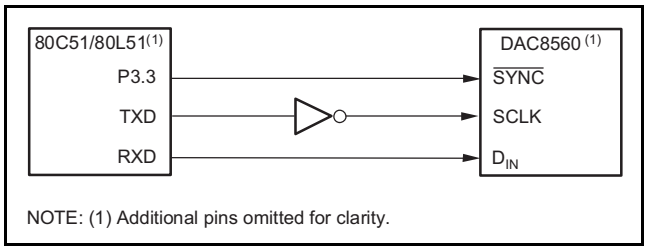


Figure 71. DAC8560 to 80C51/80L51 Interface

DAC8560 to Microwire Interface

Figure 72 shows an interface between the DAC8560 and any Microwire compatible device. Serial data is shifted out on the falling edge of the serial clock and is clocked into the DAC8560 on the rising edge of the SK signal.

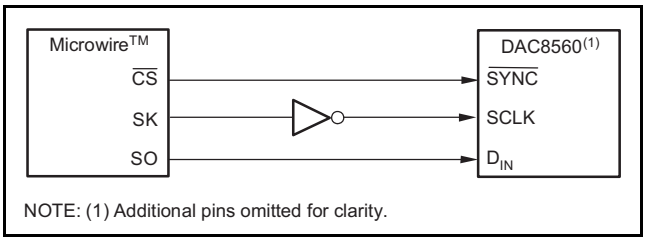


Figure 72. DAC8560 to Microwire Interface

DAC8560 to 68HC11 Interface

Figure 73 shows a serial interface between the DAC8560 and the 68HC11 microcontroller. SCK of the 68HC11 drives the SCLK of the DAC8560, while the MOSI output drives the serial data line of the DAC. The SYNC signal is derived from a port line (PC7), similar to the 8051 diagram.

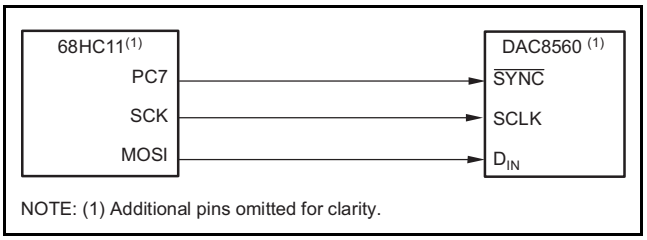


Figure 73. DAC8560 to 68HC11 Interface

The 68HC11 should be configured so that its CPOL bit is '0' and its CPHA bit is '1'. This configuration causes data appearing on the MOSI output to be valid on the falling edge of SCK. When data is being transmitted to the DAC, the SYNC line is held LOW (PC7). Serial data from the 68HC11 is transmitted in 8-bit bytes with only eight falling clock edges occurring in the transmit cycle. (Data is transmitted MSB first.) In order to load data to the DAC8560, PC7 is left LOW after the first eight bits are transferred, then a second and third serial write operation is performed to the DAC. PC7 is taken HIGH at the end of this procedure.

LAYOUT

A precision analog component requires careful layout, adequate bypassing, and clean, well-regulated power supplies.

The DAC8560 offers single-supply operation, and it often is used in close proximity with digital logic, microcontrollers, microprocessors, and digital signal processors. The more digital logic present in the design and the higher the switching speed, the more difficult it is to keep digital noise from appearing at the output.

As a result of the single ground pin of the DAC8560, all return currents, including digital and analog return currents for the DAC, must flow through a single point. Ideally, GND would be connected directly to an analog ground plane. This plane would be separate from the ground connection for the digital components until they were connected at the power-entry point of the system.

The power applied to V_{DD} should be well regulated and low noise. Switching power supplies and DC/DC converters often have high-frequency glitches or spikes riding on the output voltage. In addition, digital components can create similar high-frequency spikes as their internal logic switches states. This noise can easily couple into the DAC output voltage through various paths between the power connections and analog output.

As with the GND connection, V_{DD} should be connected to a power-supply plane or trace that is separate from the connection for digital logic until they are connected at the power-entry point. In addition, a 1µF to 10µF capacitor and 0.1µF bypass capacitor are strongly recommended. In some situations, additional bypassing may be required, such as a 100µF electrolytic capacitor or even a *Pi* filter made up of inductors and capacitors – all designed to essentially low-pass filter the supply, removing the high-frequency noise.

REVISION HISTORY

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Original (December 2006) to Revision A **Page**

- Changed Output Voltage parameter min/max values from 2.4995 and 2.5005 to 2.4975 and 2.5025, respectively 4
- Changed Initial Accuracy parameter min/max values from –0.02 and 0.02 to –0.1 and 0.1, respectively 4

Changes from Revision A (May 2011) to Revision B **Page**

- Changed Revision date from A, May 2011 to B, November 2011 1
- Changed "Zero-code error drift" in the ELEC CHARA table, TYP from ±20 to ±4 3

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
DAC8560IADGKR	ACTIVE	VSSOP	DGK	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU | CU NIPDAUAG	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560IADGKRG4	ACTIVE	VSSOP	DGK	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560IADGKT	ACTIVE	VSSOP	DGK	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU | CU NIPDAUAG	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560IADGKTG4	ACTIVE	VSSOP	DGK	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560IBDGKR	ACTIVE	VSSOP	DGK	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU | CU NIPDAUAG	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560IBDGKRG4	ACTIVE	VSSOP	DGK	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560IBDGKT	ACTIVE	VSSOP	DGK	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU | CU NIPDAUAG	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560IBDGKTG4	ACTIVE	VSSOP	DGK	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560ICDGKR	ACTIVE	VSSOP	DGK	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU | CU NIPDAUAG	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560ICDGKRG4	ACTIVE	VSSOP	DGK	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560ICDGKT	ACTIVE	VSSOP	DGK	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU | CU NIPDAUAG	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560ICDGKTG4	ACTIVE	VSSOP	DGK	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560IDDGKR	ACTIVE	VSSOP	DGK	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU | CU NIPDAUAG	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560IDDGKRG4	ACTIVE	VSSOP	DGK	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560IDDGKT	ACTIVE	VSSOP	DGK	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU | CU NIPDAUAG	Level-2-260C-1 YEAR	-40 to 105	D860	Samples
DAC8560IDDGKTG4	ACTIVE	VSSOP	DGK	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 105	D860	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

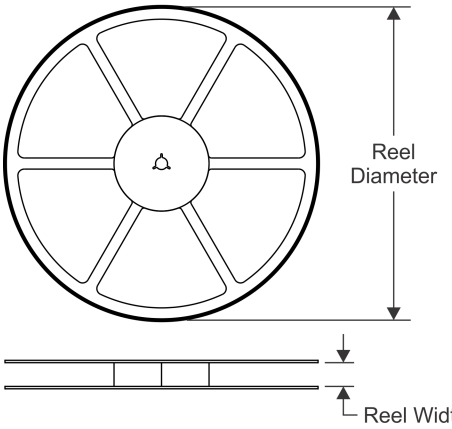
(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

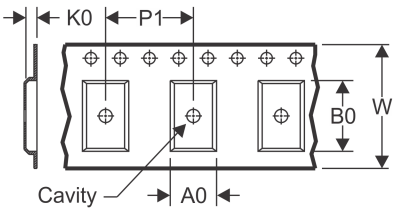
(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

TAPE AND REEL INFORMATION

REEL DIMENSIONS

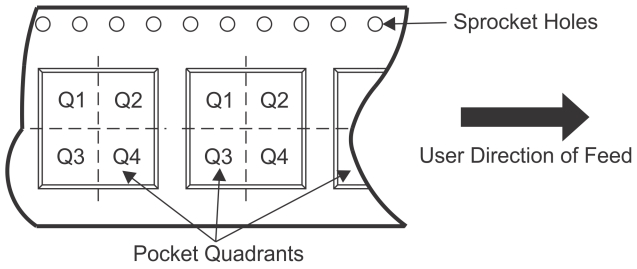


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

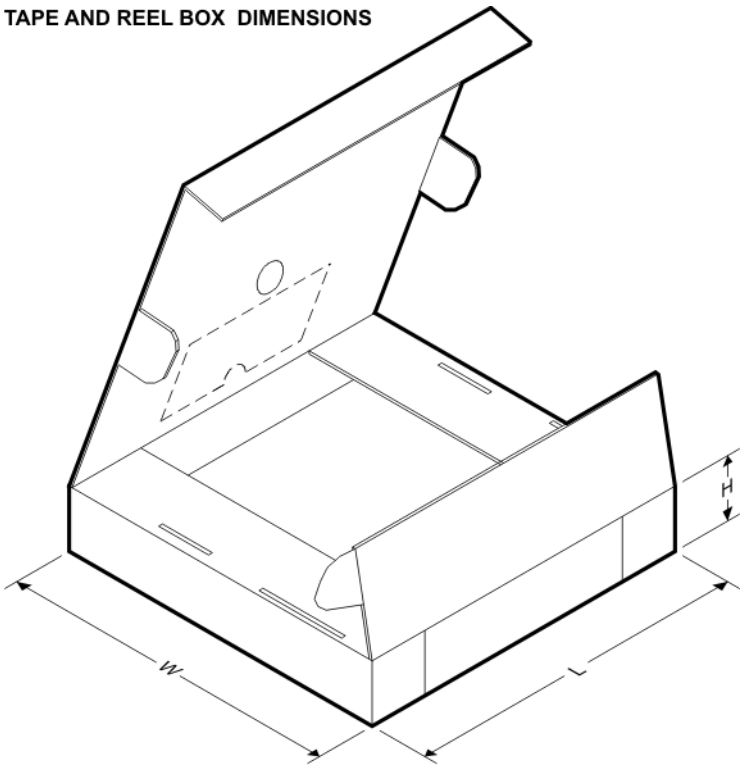
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
DAC8560IADGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
DAC8560IADGKT	VSSOP	DGK	8	250	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
DAC8560IBDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
DAC8560IBDGKT	VSSOP	DGK	8	250	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
DAC8560ICDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
DAC8560ICDGKT	VSSOP	DGK	8	250	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
DAC8560IDDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
DAC8560IDDGKT	VSSOP	DGK	8	250	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1

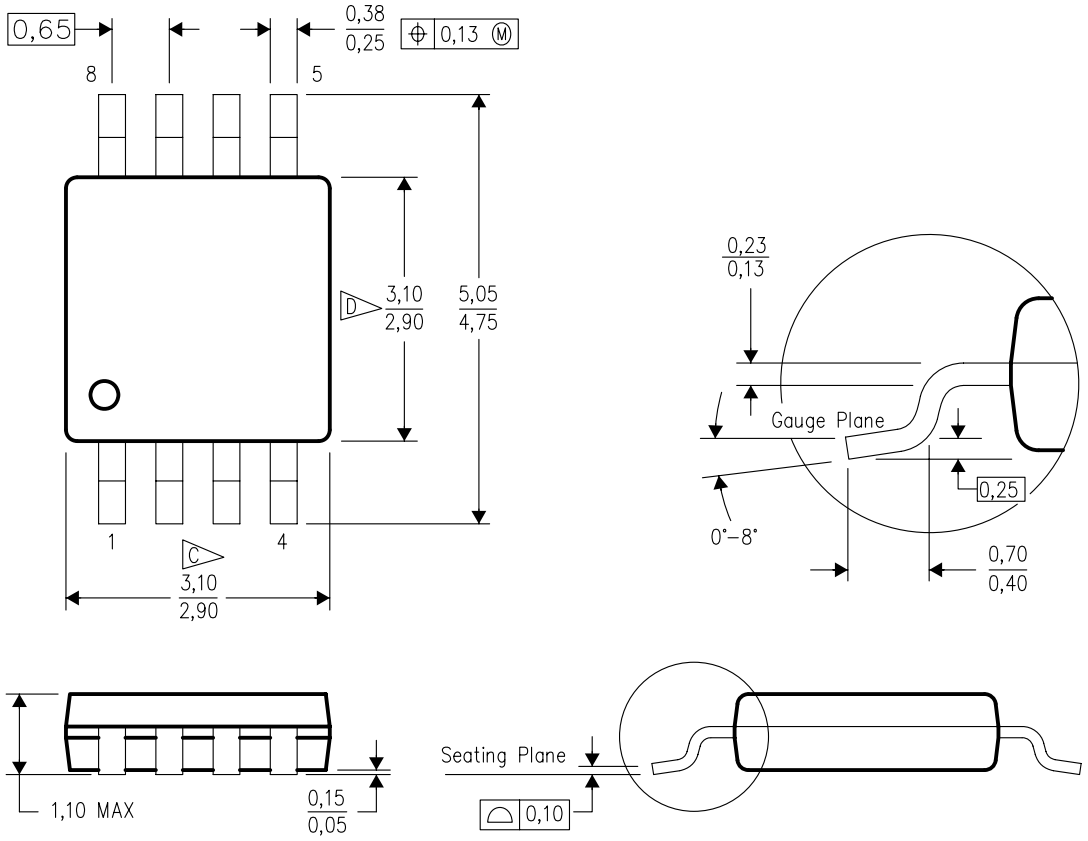
TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
DAC8560IADGKR	VSSOP	DGK	8	2500	367.0	367.0	35.0
DAC8560IADGKT	VSSOP	DGK	8	250	367.0	367.0	35.0
DAC8560IBDGKR	VSSOP	DGK	8	2500	367.0	367.0	35.0
DAC8560IBDGKT	VSSOP	DGK	8	250	367.0	367.0	35.0
DAC8560ICDGKR	VSSOP	DGK	8	2500	367.0	367.0	35.0
DAC8560ICDGKT	VSSOP	DGK	8	250	367.0	367.0	35.0
DAC8560IDDGKR	VSSOP	DGK	8	2500	367.0	367.0	35.0
DAC8560IDDGKT	VSSOP	DGK	8	250	367.0	367.0	35.0

DGK (S–PDSO–G8) PLASTIC SMALL–OUTLINE PACKAGE



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NOTES:
A. All linear dimensions are in millimeters.
B. This drawing is subject to change without notice.
C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per end.
D. Body width does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
E. Falls within JEDEC MO–187 variation AA, except interlead flash.

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